

Welcome to **E-XFL.COM** 

**Understanding Embedded - FPGAs (Field Programmable Gate Array)** 

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1176
Number of Logic Elements/Cells	5292
Total RAM Bits	57344
Number of I/O	180
Number of Gates	236666
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-BBGA
Supplier Device Package	256-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv200-5bg256c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



## **Virtex Architecture**

Virtex devices feature a flexible, regular architecture that comprises an array of configurable logic blocks (CLBs) surrounded by programmable input/output blocks (IOBs), all interconnected by a rich hierarchy of fast, versatile routing resources. The abundance of routing resources permits the Virtex family to accommodate even the largest and most complex designs.

Virtex FPGAs are SRAM-based, and are customized by loading configuration data into internal memory cells. In some modes, the FPGA reads its own configuration data from an external PROM (master serial mode). Otherwise, the configuration data is written into the FPGA (Select-MAP<sup>TM</sup>, slave serial, and JTAG modes).

The standard Xilinx Foundation™ and Alliance Series™ Development systems deliver complete design support for Virtex, covering every aspect from behavioral and schematic entry, through simulation, automatic design translation and implementation, to the creation, downloading, and readback of a configuration bit stream.

#### **Higher Performance**

Virtex devices provide better performance than previous generations of FPGA. Designs can achieve synchronous system clock rates up to 200 MHz including I/O. Virtex inputs and outputs comply fully with PCI specifications, and interfaces can be implemented that operate at 33 MHz or 66 MHz. Additionally, Virtex supports the hot-swapping requirements of Compact PCI.

Xilinx thoroughly benchmarked the Virtex family. While performance is design-dependent, many designs operated internally at speeds in excess of 100 MHz and can achieve 200 MHz. Table 2 shows performance data for representative circuits, using worst-case timing parameters.

Table 2: Performance for Common Circuit Functions

Function	Bits	Virtex -6
Register-to-Register		
Adder	16	5.0 ns
Audei	64	7.2 ns
Pipelined Multiplier	8 x 8	5.1 ns
	16 x 16	6.0 ns
Address Decoder	16	4.4 ns
	64	6.4 ns
16:1 Multiplexer		5.4 ns
Parity Tree	9	4.1 ns
	18	5.0 ns
	36	6.9 ns
Chip-to-Chip		
HSTL Class IV		200 MHz
LVTTL,16mA, fast slew		180 MHz



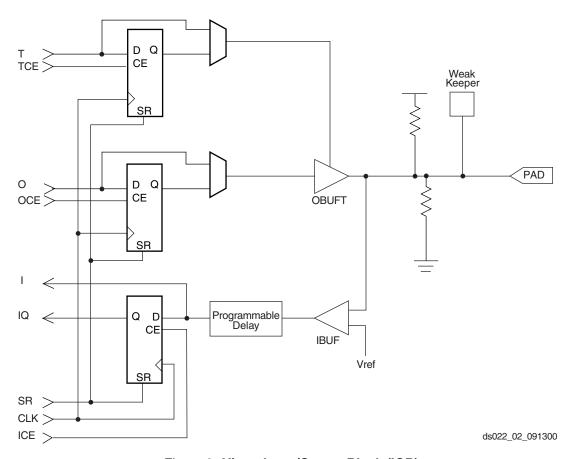


Figure 2: Virtex Input/Output Block (IOB)

Table 1: Supported Select I/O Standards

I/O Standard	Input Reference Voltage (V <sub>REF</sub> )	Output Source Voltage (V <sub>CCO</sub> )	Board Termination Voltage (V <sub>TT</sub> )	5 V Tolerant
LVTTL 2 – 24 mA	N/A	3.3	N/A	Yes
LVCMOS2	N/A	2.5	N/A	Yes
PCI, 5 V	N/A	3.3	N/A	Yes
PCI, 3.3 V	N/A	3.3	N/A	No
GTL	0.8	N/A	1.2	No
GTL+	1.0	N/A	1.5	No
HSTL Class I	0.75	1.5	0.75	No
HSTL Class III	0.9	1.5	1.5	No
HSTL Class IV	0.9	1.5	1.5	No
SSTL3 Class I &II	1.5	3.3	1.5	No
SSTL2 Class I & II	1.25	2.5	1.25	No
CTT	1.5	3.3	1.5	No
AGP	1.32	3.3	N/A	No



more I/O pins convert to  $V_{REF}$  pins. Since these are always a superset of the  $V_{REF}$  pins used for smaller devices, it is possible to design a PCB that permits migration to a larger device if necessary. All the  $V_{REF}$  pins for the largest device anticipated must be connected to the  $V_{REF}$  voltage, and not used for I/O.

In smaller devices, some  $V_{CCO}$  pins used in larger devices do not connect within the package. These unconnected pins can be left unconnected externally, or can be connected to the  $V_{CCO}$  voltage to permit migration to a larger device if necessary.

In TQ144 and PQ/HQ240 packages, all  $V_{CCO}$  pins are bonded together internally, and consequently the same  $V_{CCO}$  voltage must be connected to all of them. In the CS144 package, bank pairs that share a side are interconnected internally, permitting four choices for  $V_{CCO}$ . In both cases, the  $V_{REF}$  pins remain internally connected as eight banks, and can be used as described previously.

#### **Configurable Logic Block**

The basic building block of the Virtex CLB is the logic cell (LC). An LC includes a 4-input function generator, carry logic, and a storage element. The output from the function generator in each LC drives both the CLB output and the D input of the flip-flop. Each Virtex CLB contains four LCs, organized in two similar slices, as shown in Figure 4.

Figure 5 shows a more detailed view of a single slice.

In addition to the four basic LCs, the Virtex CLB contains logic that combines function generators to provide functions

of five or six inputs. Consequently, when estimating the number of system gates provided by a given device, each CLB counts as 4.5 LCs.

#### Look-Up Tables

Virtex function generators are implemented as 4-input look-up tables (LUTs). In addition to operating as a function generator, each LUT can provide a 16 x 1-bit synchronous RAM. Furthermore, the two LUTs within a slice can be combined to create a 16 x 2-bit or 32 x 1-bit synchronous RAM, or a 16x1-bit dual-port synchronous RAM.

The Virtex LUT can also provide a 16-bit shift register that is ideal for capturing high-speed or burst-mode data. This mode can also be used to store data in applications such as Digital Signal Processing.

#### Storage Elements

The storage elements in the Virtex slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by the function generators within the slice or directly from slice inputs, bypassing the function generators.

In addition to Clock and Clock Enable signals, each Slice has synchronous set and reset signals (SR and BY). SR forces a storage element into the initialization state specified for it in the configuration. BY forces it into the opposite state. Alternatively, these signals can be configured to operate asynchronously. All of the control signals are independently invertible, and are shared by the two flip-flops within the slice.

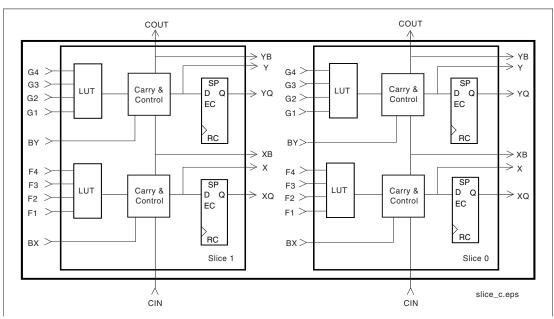


Figure 4: 2-Slice Virtex CLB



In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

Figure 10 is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

#### Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG\_IN, CFG\_OUT, and JSTART). The complete instruction set is coded as shown in Table 5.

#### Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decodes of the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

#### Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 11.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

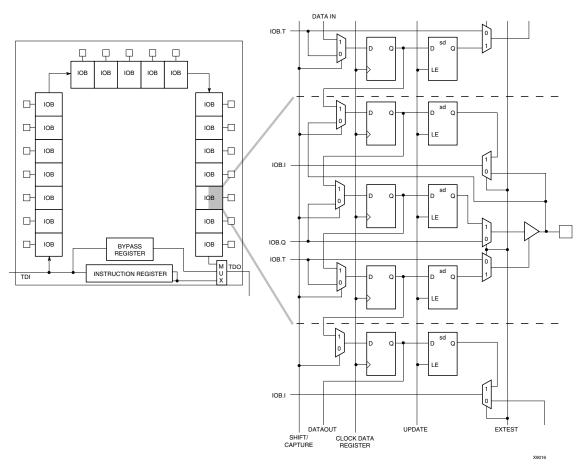


Figure 10: Virtex Series Boundary Scan Logic

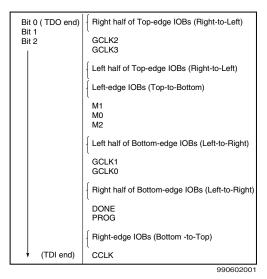


Figure 11: Boundary Scan Bit Sequence

Table 5: Boundary Scan Instructions

Boundary-Scan Command	Binary Code(4:0)	Description
EXTEST	00000	Enables boundary-scan EXTEST operation
SAMPLE/PRELOAD	00001	Enables boundary-scan SAMPLE/PRELOAD operation
USER 1	00010	Access user-defined register 1
USER 2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for read operations.
CFG_IN	00101	Access the configuration bus for write operations.
INTEST	00111	Enables boundary-scan INTEST operation
USERCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIGHZ	01010	3-states output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx reserved instructions

#### Identification Registers

The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined.

The IDCODE register has the following binary format:

vvvv:ffff:fffa:aaaa:aaaa:cccc:cccc1

where

v = the die version number

f = the family code (03h for Virtex family)

a = the number of CLB rows (ranges from 010h for XCV50 to 040h for XCV1000)

c = the company code (49h for Xilinx)

The USERCODE register is supported. By using the USER-CODE, a user-programmable identification code can be loaded and shifted out for examination. The identification code is embedded in the bitstream during bitstream generation and is valid only after configuration.

Table 6: IDCODEs Assigned to Virtex FPGAs

FPGA	IDCODE
XCV50	v0610093h
XCV100	v0614093h
XCV150	v0618093h
XCV200	v061C093h
XCV300	v0620093h
XCV400	v0628093h
XCV600	v0630093h
XCV800	v0638093h
XCV1000	v0640093h

#### Including Boundary Scan in a Design

Since the boundary scan pins are dedicated, no special element needs to be added to the design unless an internal data register (USER1 or USER2) is desired.

If an internal data register is used, insert the boundary scan symbol and connect the necessary pins as appropriate.

## **Development System**

Virtex FPGAs are supported by the Xilinx Foundation and Alliance CAE tools. The basic methodology for Virtex design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing design-



ers with a common user interface regardless of their choice of entry and verification tools. The XDM software simplifies the selection of implementation options with pull-down menus and on-line help.

Application programs ranging from schematic capture to Placement and Routing (PAR) can be accessed through the XDM software. The program command sequence is generated prior to execution, and stored for documentation.

Several advanced software features facilitate Virtex design. RPMs, for example, are schematic-based macros with relative location constraints to guide their placement. They help ensure optimal implementation of common functions.

For HDL design entry, the Xilinx FPGA Foundation development system provides interfaces to the following synthesis design environments.

- Synopsys (FPGA Compiler, FPGA Express)
- Exemplar (Spectrum)
- Synplicity (Synplify)

For schematic design entry, the Xilinx FPGA Foundation and alliance development system provides interfaces to the following schematic-capture design environments.

- Mentor Graphics V8 (Design Architect, QuickSim II)
- Viewlogic Systems (Viewdraw)

Third-party vendors support many other environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Virtex FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The "soft macro" portion of the library contains detailed descriptions of common logic functions, but does not contain any partitioning or placement information. The performance of these macros depends, therefore, on the partitioning and placement obtained during implementation.

RPMs, on the other hand, do contain predetermined partitioning and placement information that permits optimal implementation of these functions. Users can create their own library of soft macros or RPMs based on the macros and primitives in the standard library.

The design environment supports hierarchical design entry, with high-level schematics that comprise major functional blocks, while lower-level schematics define the logic in these blocks. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical

design, thus allowing the most convenient entry method to be used for each portion of the design.

## **Design Implementation**

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF net list for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floor planning.

The implementation software incorporates Timing Wizard® timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered on a schematic in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

#### **Design Verification**

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the net list for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the TRACE® static timing analyzer.

For in-circuit debugging, the development system includes a download and readback cable. This cable connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can single-step the logic, readback the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.



# **Configuration**

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- PROGRAM pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The PROGRAM pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a  $V_{CCO}$  of 3.3 V to permit LVTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

#### **Configuration Modes**

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- · Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

Table 7: Configuration Codes

Configuration Mode	M2	M1	МО	<b>CCLK Direction</b>	Data Width	Serial D <sub>out</sub>	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

#### Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:

http://www.xilinx.com/bvdocs/publications/ds026.pdf.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for

mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the INIT pins of all daisy-chained FPGAs are High.



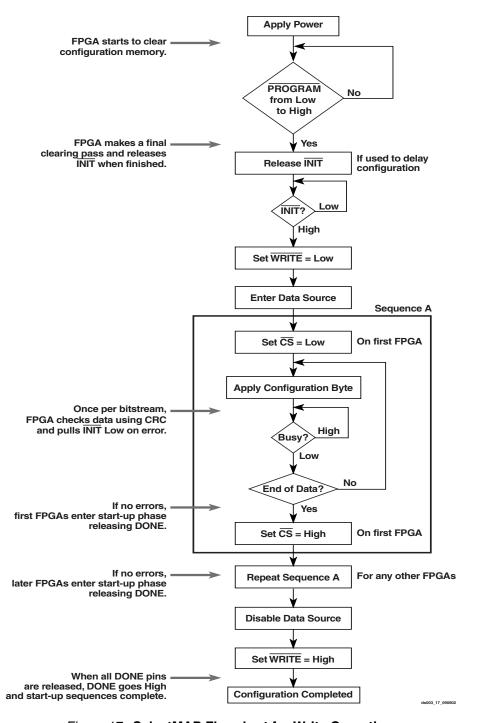


Figure 17: SelectMAP Flowchart for Write Operation

#### **Abort**

During a given assertion of  $\overline{\text{CS}}$ , the user cannot switch from a write to a read, or vice-versa. This action causes the current packet command to be aborted. The device will remain BUSY until the aborted operation has completed. Following an abort, data is assumed to be unaligned to word boundar-

ies, and the FPGA requires a new synchronization word prior to accepting any new packets.

To initiate an abort during a write operation, de-assert WRITE. At the rising edge of CCLK, an abort is initiated, as shown in Figure 18.



## **Virtex DC Characteristics**

## **Absolute Maximum Ratings**

Symbol	Description <sup>(1)</sup>			Units
V <sub>CCINT</sub>	Supply voltage relative to GND <sup>(2)</sup>		-0.5 to 3.0	V
V <sub>CCO</sub>	Supply voltage relative to GND <sup>(2)</sup>	Supply voltage relative to GND <sup>(2)</sup>		V
V <sub>REF</sub>	Input Reference Voltage	-0.5 to 3.6	V	
V	Input voltage relative to GND <sup>(3)</sup>	Using V <sub>REF</sub>	-0.5 to 3.6	V
V <sub>IN</sub>		Internal threshold	-0.5 to 5.5	V
V <sub>TS</sub>	Voltage applied to 3-state output	Voltage applied to 3-state output		V
V <sub>CC</sub>	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T <sub>STG</sub>	Storage temperature (ambient)		-65 to +150	°C
TJ	Junction temperature <sup>(4)</sup>	Plastic Packages	+125	°C

#### Notes:

- Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress
  ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions
  is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
- 2. Power supplies can turn on in any order.
- 3. For protracted periods (e.g., longer than a day),  $V_{IN}$  should not exceed  $V_{CCO}$  by more than 3.6 V.
- 4. For soldering guidelines and thermal considerations, see the "Device Packaging" information on <a href="https://www.xilinx.com">www.xilinx.com</a>.

## **Recommended Operating Conditions**

Symbol	Description			Max	Units
V <sub>CCINT</sub> <sup>(1)</sup>	Input Supply voltage relative to GND, $T_J = 0$ °C to +85°C	Commercial	2.5 – 5%	2.5 + 5%	V
Input Supply voltage relative to GND, $T_J = -40^{\circ}$ C to +100		Industrial	2.5 – 5%	2.5 + 5%	V
V <sub>CCO</sub> <sup>(4)</sup>	Supply voltage relative to GND, T <sub>J</sub> = 0 °C to +85°C	Commercial	1.4	3.6	V
, CCO,	Supply voltage relative to GND, $T_J = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$ Industrial		1.4	3.6	V
T <sub>IN</sub>	Input signal transition time			250	ns

- Correct operation is guaranteed with a minimum V<sub>CCINT</sub> of 2.375 V (Nominal V<sub>CCINT</sub> -5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V<sub>CCINT</sub> below the specified range.
- 2. At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
- 3. Input and output measurement threshold is  $\sim$ 50% of  $V_{CC}$ .
- Min and Max values for V<sub>CCO</sub> are I/O Standard dependant.



			Speed Grade				
Description	Device	Symbol	Min	-6	-5	-4	Units
Setup and Hold Times with respect to Clock CLK at IOB input $\operatorname{register}^{(1)}$		CLK at IOB input		Setup	Time / Hol	d Time	
Pad, no delay	All	T <sub>IOPICK</sub> /T <sub>IOICKP</sub>	0.8 / 0	1.6 / 0	1.8 / 0	2.0 / 0	ns, min
Pad, with delay	XCV50	T <sub>IOPICKD</sub> /T <sub>IOICKPD</sub>	1.9 / 0	3.7 / 0	4.1 / 0	4.7 / 0	ns, min
	XCV100		1.9 / 0	3.7 / 0	4.1 / 0	4.7 / 0	ns, min
	XCV150		1.9 / 0	3.8 / 0	4.3 / 0	4.9 / 0	ns, min
	XCV200		2.0 / 0	3.9 / 0	4.4 / 0	5.0 / 0	ns, min
	XCV300		2.0 / 0	3.9 / 0	4.4 / 0	5.0 / 0	ns, min
	XCV400		2.1 / 0	4.1 / 0	4.6 / 0	5.3 / 0	ns, min
	XCV600		2.1 / 0	4.2 / 0	4.7 / 0	5.4 / 0	ns, min
	XCV800		2.2 / 0	4.4 / 0	4.9 / 0	5.6 / 0	ns, min
	XCV1000		2.3 / 0	4.5 / 0	5.0 / 0	5.8 / 0	ns, min
ICE input	All	T <sub>IOICECK</sub> /T <sub>IOCKICE</sub>	0.37/ 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, max
Set/Reset Delays							
SR input (IFF, synchronous)	All	T <sub>IOSRCKI</sub>	0.49	1.0	1.1	1.3	ns, max
SR input to IQ (asynchronous)	All	T <sub>IOSRIQ</sub>	0.70	1.4	1.6	1.8	ns, max
GSR to output IQ	All	T <sub>GSRQ</sub>	4.9	9.7	10.9	12.5	ns, max

<sup>1.</sup> A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

<sup>2.</sup> Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see Table 3.



# Calculation of T<sub>ioop</sub> as a Function of Capacitance

 $T_{ioop}$  is the propagation delay from the O Input of the IOB to the pad. The values for  $T_{ioop}$  were based on the standard capacitive load (CsI) for each I/O standard as listed in Table 2.

Table 2: Constants for Calculating T<sub>ioop</sub>

Standard	Csl (pF)	fl (ns/pF)
LVTTL Fast Slew Rate, 2mA drive	35	0.41
LVTTL Fast Slew Rate, 4mA drive	35	0.20
LVTTL Fast Slew Rate, 6mA drive	35	0.13
LVTTL Fast Slew Rate, 8mA drive	35	0.079
LVTTL Fast Slew Rate, 12mA drive	35	0.044
LVTTL Fast Slew Rate, 16mA drive	35	0.043
LVTTL Fast Slew Rate, 24mA drive	35	0.033
LVTTL Slow Slew Rate, 2mA drive	35	0.41
LVTTL Slow Slew Rate, 4mA drive	35	0.20
LVTTL Slow Slew Rate, 6mA drive	35	0.100
LVTTL Slow Slew Rate, 8mA drive	35	0.086
LVTTL Slow Slew Rate, 12mA drive	35	0.058
LVTTL Slow Slew Rate, 16mA drive	35	0.050
LVTTL Slow Slew Rate, 24mA drive	35	0.048
LVCMOS2	35	0.041
PCI 33MHz 5V	50	0.050
PCI 33MHZ 3.3 V	10	0.050
PCI 66 MHz 3.3 V	10	0.033
GTL	0	0.014
GTL+	0	0.017
HSTL Class I	20	0.022
HSTL Class III	20	0.016
HSTL Class IV	20	0.014
SSTL2 Class I	30	0.028
SSTL2 Class II	30	0.016
SSTL3 Class I	30	0.029
SSTL3 Class II	30	0.016
СТТ	20	0.035
AGP	10	0.037

#### Notes:

- I/O parameter measurements are made with the capacitance values shown above. See Application Note XAPP133 on <u>www.xilinx.com</u> for appropriate terminations.
- I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

For other capacitive loads, use the formulas below to calculate the corresponding  $T_{\text{ioop}}$ .

$$T_{ioop} = T_{ioop} + T_{opadjust} + (C_{load} - C_{sl}) * fl$$

Where:

 $T_{opadjust}$  is reported above in the Output Delay Adjustment section.

C<sub>load</sub> is the capacitive load for the design.

Table 3: Delay Measurement Methodology

Standard	ν <sub>L</sub> (1)	V <sub>H</sub> <sup>(1)</sup>	Meas. Point	V <sub>REF</sub> Typ <sup>(2)</sup>
LVTTL	0	3	1.4	-
LVCMOS2	0	2.5	1.125	-
PCI33_5	Pe	er PCI Spec		-
PCI33_3	Pe	er PCI Spec		-
PCI66_3	Pe	er PCI Spec		-
GTL	V <sub>REF</sub> -0.2	V <sub>REF</sub> +0.2	V <sub>REF</sub>	0.80
GTL+	V <sub>REF</sub> -0.2	V <sub>REF</sub> +0.2	V <sub>REF</sub>	1.0
HSTL Class I	V <sub>REF</sub> -0.5	V <sub>REF</sub> +0.5	V <sub>REF</sub>	0.75
HSTL Class III	V <sub>REF</sub> -0.5	V <sub>REF</sub> +0.5	V <sub>REF</sub>	0.90
HSTL Class IV	V <sub>REF</sub> -0.5	V <sub>REF</sub> +0.5	V <sub>REF</sub>	0.90
SSTL3 I & II	V <sub>REF</sub> -1.0	V <sub>REF</sub> +1.0	V <sub>REF</sub>	1.5
SSTL2 I & II	V <sub>REF</sub> -0.75	V <sub>REF</sub> +0.75	$V_{REF}$	1.25
CTT	V <sub>REF</sub> -0.2	V <sub>REF</sub> +0.2	V <sub>REF</sub>	1.5
AGP	V <sub>REF</sub> – (0.2xV <sub>CCO</sub> )	V <sub>REF</sub> + (0.2xV <sub>CCO</sub> )	V <sub>REF</sub>	Per AGP Spec

- Input waveform switches between V<sub>L</sub>and V<sub>H</sub>.
- 2. Measurements are made at VREF (Typ), Maximum, and Minimum. Worst-case values are reported.
- I/O parameter measurements are made with the capacitance values shown in Table 2. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
- 4. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.



## **Clock Distribution Guidelines**

			Speed Grade			
Description	Device	Symbol	-6	-5	-4	Units
Global Clock Skew <sup>(1)</sup>						
Global Clock Skew between IOB Flip-flops	XCV50	T <sub>GSKEWIOB</sub>	0.10	0.12	0.14	ns, max
	XCV100		0.12	0.13	0.15	ns, max
	XCV150		0.12	0.13	0.15	ns, max
	XCV200		0.13	0.14	0.16	ns, max
	XCV300		0.14	0.16	0.18	ns, max
	XCV400		0.13	0.13	0.14	ns, max
	XCV600		0.14	0.15	0.17	ns, max
	XCV800		0.16	0.17	0.20	ns, max
	XCV1000		0.20	0.23	0.25	ns, max

#### Notes:

## **Clock Distribution Switching Characteristics**

		Speed Grade				
Description	Symbol	Min	-6	<b>-</b> 5	-4	Units
GCLK IOB and Buffer						
Global Clock PAD to output.	T <sub>GPIO</sub>	0.33	0.7	0.8	0.9	ns, max
Global Clock Buffer I input to O output	T <sub>GIO</sub>	0.34	0.7	0.8	0.9	ns, max

<sup>1.</sup> These clock-skew delays are provided for guidance only. They reflect the delays encountered in a typical design under worst-case conditions. Precise values for a particular design are provided by the timing analyzer.



## **CLB Switching Characteristics**

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays		•				
4-input function: F/G inputs to X/Y outputs	T <sub>ILO</sub>	0.29	0.6	0.7	0.8	ns, max
5-input function: F/G inputs to F5 output	T <sub>IF5</sub>	0.32	0.7	0.8	0.9	ns, max
5-input function: F/G inputs to X output	T <sub>IF5X</sub>	0.36	0.8	0.8	1.0	ns, max
6-input function: F/G inputs to Y output via F6 MUX	T <sub>IF6Y</sub>	0.44	0.9	1.0	1.2	ns, max
6-input function: F5IN input to Y output	T <sub>F5INY</sub>	0.17	0.32	0.36	0.42	ns, max
Incremental delay routing through transparent latch to XQ/YQ outputs	T <sub>IFNCTL</sub>	0.31	0.7	0.7	0.8	ns, max
BY input to YB output	T <sub>BYYB</sub>	0.27	0.53	0.6	0.7	ns, max
Sequential Delays						T.
FF Clock CLK to XQ/YQ outputs	T <sub>CKO</sub>	0.54	1.1	1.2	1.4	ns, max
Latch Clock CLK to XQ/YQ outputs	T <sub>CKLO</sub>	0.6	1.2	1.4	1.6	ns, max
Setup and Hold Times before/after Clock CLK <sup>(1)</sup>	Setup Time			ne / Hold Time		
4-input function: F/G Inputs	T <sub>ICK</sub> /T <sub>CKI</sub>	0.6 / 0	1.2 / 0	1.4 / 0	1.5 / 0	ns, min
5-input function: F/G inputs	T <sub>IF5CK</sub> /T <sub>CKIF5</sub>	0.7 / 0	1.3 / 0	1.5 / 0	1.7 / 0	ns, min
6-input function: F5IN input	T <sub>F5INCK</sub> /T <sub>CKF5IN</sub>	0.46 / 0	1.0 / 0	1.1 / 0	1.2 / 0	ns, min
6-input function: F/G inputs via F6 MUX	T <sub>IF6CK</sub> /T <sub>CKIF6</sub>	0.8 / 0	1.5 / 0	1.7 / 0	1.9 / 0	ns, min
BX/BY inputs	$T_{DICK}/T_{CKDI}$	0.30 / 0	0.6 / 0	0.7 / 0	0.8 / 0	ns, min
CE input	T <sub>CECK</sub> /T <sub>CKCE</sub>	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR/BY inputs (synchronous)	$T_{RCK}T_{CKR}$	0.33 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T <sub>CH</sub>	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	$T_CL$	0.8	1.5	1.7	2.0	ns, min
Set/Reset						
Minimum Pulse Width, SR/BY inputs	T <sub>RPW</sub>	1.3	2.5	2.8	3.3	ns, min
Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	T <sub>RQ</sub>	0.54	1.1	1.3	1.4	ns, max
Delay from GSR to XQ/YQ outputs	T <sub>IOGSRQ</sub>	4.9	9.7	10.9	12.5	ns, max
Toggle Frequency (MHz) (for export control)	F <sub>TOG</sub> (MHz)	625	333	294	250	MHz

<sup>1.</sup> A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



## Global Clock Set-Up and Hold for LVTTL Standard, without DLL

Description	Symbol	Device	Min	-6	-5	-4	Units
Input Setup and Hold Time Relat standards, adjust the setup time of					For data inp	ut with diffe	rent
Full Delay Global Clock and IFF, without	T <sub>PSFD</sub> /T <sub>PHFD</sub>	XCV50	0.6 / 0	2.3 / 0	2.6 / 0	2.9 / 0	ns, min
DLL		XCV100	0.6 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
		XCV150	0.6 / 0	2.4 / 0	2.7 / 0	3.1 / 0	ns, min
		XCV200	0.7 / 0	2.5 / 0	2.8 / 0	3.2 / 0	ns, min
		XCV300	0.7 / 0	2.5 / 0	2.8 / 0	3.2 / 0	ns, min
		XCV400	0.7 / 0	2.6 / 0	2.9 / 0	3.3 / 0	ns, min
		XCV600	0.7 / 0	2.6 / 0	2.9 / 0	3.3 / 0	ns, min
		XCV800	0.7 / 0	2.7 / 0	3.1 / 0	3.5 / 0	ns, min
		XCV1000	0.7 / 0	2.8 / 0	3.1 / 0	3.6 / 0	ns, min

IFF = Input Flip-Flop or Latch

#### Notes: Notes:

- 1. Set-up time is measured relative to the Global Clock input signal with the fastest route and the lightest load. Hold time is measured relative to the Global Clock input signal with the slowest route and heaviest load.
- 2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Date	Version	Revision
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul> <li>Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices.</li> <li>Corrected Units column in table under IOB Input Switching Characteristics.</li> <li>Added values to table under CLB SelectRAM Switching Characteristics.</li> </ul>
10/00	2.4	<ul> <li>Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18.</li> <li>Corrected BG256 Pin Function Diagram.</li> </ul>
04/02/01	2.5	<ul> <li>Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL.</li> <li>Converted file to modularized format. See the Virtex Data Sheet section.</li> </ul>
04/19/01	2.6	Clarified TIOCKP and TIOCKON IOB Output Switching Characteristics descriptors.
07/19/01	2.7	Under Absolute Maximum Ratings, changed (T <sub>SOL</sub> ) to 220 °C.
07/26/01	2.8	Removed T <sub>SOL</sub> parameter and added footnote to Absolute Maximum Ratings table.
10/29/01	2.9	<ul> <li>Updated the speed grade designations used in data sheets, and added Table 1, which shows the current speed grade designation for each device.</li> </ul>
02/01/02	3.0	Added footnote to DC Input and Output Levels table.
07/19/02	3.1	<ul> <li>Removed mention of MIL-M-38510/605 specification.</li> <li>Added link to xapp158 from the Power-On Power Supply Requirements section.</li> </ul>
09/10/02	3.2	<ul> <li>Added Clock CLK to IOB Input Switching Characteristics and IOB Output Switching Characteristics.</li> </ul>
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

## **Virtex Data Sheet**

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs:
   DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)



Table 3: Virtex Pinout Tables (BGA)

Pin Name	Device	BG256	BG352	BG432	BG560
GCK0	All	Y11	AE13	AL16	AL17
GCK1	All	Y10	AF14	AK16	AJ17
GCK2	All	A10	B14	A16	D17
GCK3	All	B10	D14	D17	A17
MO	All	Y1	AD24	AH28	AJ29
M1	All	U3	AB23	AH29	AK30
M2	All	W2	AC23	AJ28	AN32
CCLK	All	B19	C3	D4	C4
PROGRAM	All	Y20	AC4	АН3	AM1
DONE	All	W19	AD3	AH4	AJ5
INIT	All	U18	AD2	AJ2	AH5
BUSY/DOUT	All	D18	E4	D3	D4
D0/DIN	All	C19	D3	C2	E4
D1	All	E20	G1	K4	K3
D2	All	G19	J3	K2	L4
D3	All	J19	M3	P4	P3
D4	All	M19	R3	V4	W4
D5	All	P19	U4	AB1	AB5
D6	All	T20	V3	AB3	AC4
D7	All	V19	AC3	AG4	AJ4
WRITE	All	A19	D5	B4	D6
CS	All	B18	C4	D5	A2
TDI	All	C17	В3	В3	D5
TDO	All	A20	D4	C4	E6
TMS	All	D3	D23	D29	B33
TCK	All	A1	C24	D28	E29
DXN	All	W3	AD23	AH27	AK29
DXP	All	V4	AE24	AK29	AJ28



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V <sub>REF</sub> Bank 1	XCV50	B9, C11	N/A	N/A	N/A
(VREF pins are listed	XCV100/150	+ E11	A18, B13, E14	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ A14	+ A19	N/A	N/A
the required device and all smaller devices	XCV400	N/A	N/A	A14, C20, C21, D15, G16	N/A
listed in the same package.) Within each bank, if	XCV600	N/A	N/A	+ B19	B6, B8, B18, D11, D13, D17
input reference voltage	XCV800	N/A	N/A	+ A17	+ B14
is not required, all V <sub>REF</sub> pins are general I/O.	XCV1000	N/A	N/A	N/A	+ B5
V <sub>REF</sub> , Bank 2	XCV50	F13, H13	N/A	N/A	N/A
(V <sub>REF</sub> pins are listed	XCV100/150	+ F14	F21, H18, K21	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ E13	+ D22	N/A	N/A
the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V <sub>REF</sub> pins are general I/O.	XCV400	N/A	N/A	F24, H23, K20, M23, M26	N/A
	XCV600	N/A	N/A	+ G26	G1, H4, J1, L2, V5, W3
	XCV800	N/A	N/A	+ K25	+ N1
	XCV1000	N/A	N/A	N/A	+ D2
V <sub>REF</sub> , Bank 3	XCV50	K16, L14	N/A	N/A	N/A
(V <sub>REF</sub> pins are listed	XCV100/150	+ L13	N21, R19, U21	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ M13	+ U20	N/A	N/A
the required device and all smaller devices listed in the same package.) Within each bank, if	XCV400	N/A	N/A	R23, R25, U21, W22, W23	N/A
	XCV600	N/A	N/A	+ W26	AC1, AJ2, AK3, AL4, AR1, Y1
input reference voltage	XCV800	N/A	N/A	+ U25	+ AF3
is not required, all V <sub>REF</sub> pins are general I/O.	XCV1000	N/A	N/A	N/A	+ AP4



## **TQ144 Pin Function Diagram**

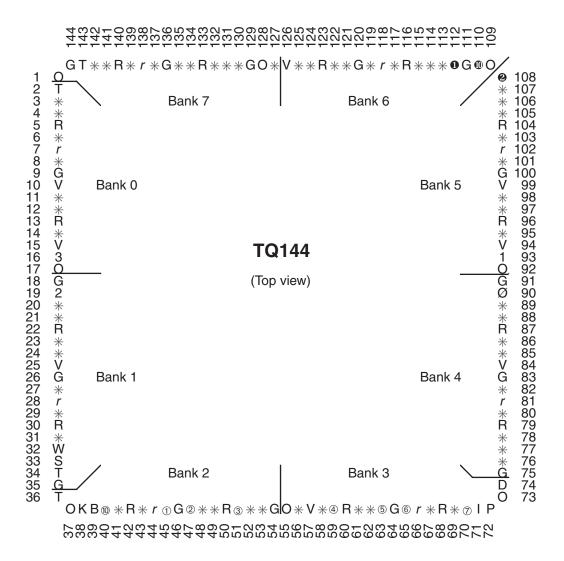
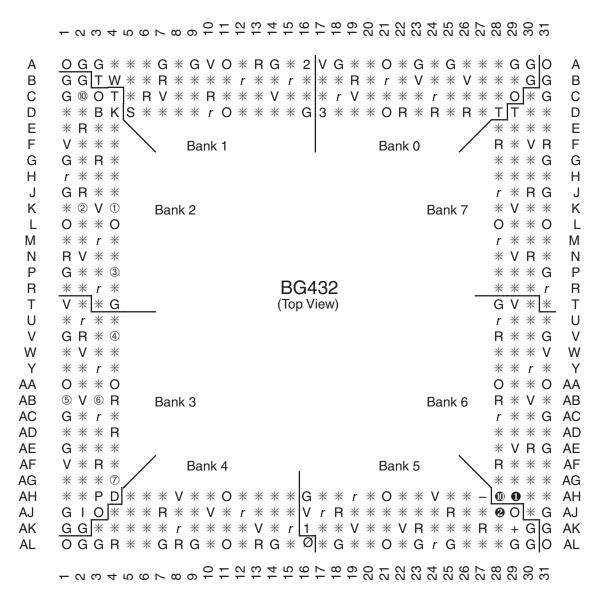


Figure 2: TQ144 Pin Function Diagram



## **BG432 Pin Function Diagram**



DS003\_21\_100300

Figure 6: BG432 Pin Function Diagram



# **Revision History**

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T <sub>IJITCC</sub> parameter, changed T <sub>OJIT</sub> to T <sub>OPHASE</sub> .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V <sub>CCO</sub> in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul> <li>Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices.</li> <li>Corrected Units column in table under IOB Input Switching Characteristics.</li> <li>Added values to table under CLB SelectRAM Switching Characteristics.</li> </ul>
10/00	2.4	<ul> <li>Corrected pinout info for devices in the BG256, BG432, and BG560 pkgs in Table 18.</li> <li>Corrected BG256 Pin Function Diagram.</li> </ul>
04/02/01	2.5	<ul> <li>Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL.</li> <li>Converted file to modularized format. See section Virtex Data Sheet, below.</li> </ul>
04/19/01	2.6	Corrected pinout information for FG676 device in Table 4. (Added AB22 pin.)
07/19/01	2.7	<ul> <li>Clarified V<sub>CCINT</sub> pinout information and added AE19 pin for BG352 devices in Table 3.</li> <li>Changed pinouts listed for BG352 XCV400 devices in banks 0 thru 7.</li> </ul>
07/19/02	2.8	Changed pinouts listed for GND in TQ144 devices (see Table 2).
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

## **Virtex Data Sheet**

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs:
   DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)